	arc	 	 _	

Application/Control No.	Applicant(s)/Patent under Reexamination	_
09/731,571	HUFF ET AL.	
Examiner	Art Unit	_
Fllen C. Tran	2134	

	SEARCHED				
Class	Subclass	Date	Examiner		
713	168	3/27/2006	ECT		
380	270	3/27/2006	ECT		
726	3	3/31/2006	ECT		
709	229	3/31/2006	ECT		
		,			

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
Interferen	Interference Search		ECT	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	3/27/2006	ECT	
NPL IEEE XPLORE	3/27/2006	ECT	
PALM INVENTOR	3/27/2006	ECT	
		·	